

Resource Summary Report

Generated by SPARC SAWG on Aug 8, 2026

FEI: Meridian V System for Semiconductors

RRID:SCR_019889

Type: Tool

Proper Citation

FEI: Meridian V System for Semiconductors (RRID:SCR_019889)

Resource Information

URL: <https://www.fei.com/products/efa/meridian-v-for-semiconductors/>

Proper Citation: FEI: Meridian V System for Semiconductors (RRID:SCR_019889)

Description: Electrical failure analysis system for semiconductors with optimized dynamic LSM platform that supports automated test equipment docking and back side analysis with laser voltage probing, laser voltage imaging, and laser simulation for critical path analysis.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Meridian V System for Semiconductors

Resource ID: SCR_019889

Alternate IDs: Model_Number_Meridian_V

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260808T190143+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Meridian V System for Semiconductors.

No alerts have been found for FEI: Meridian V System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.